Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/679,055	HANKO ET AL.	
Examiner	**Art Unit**	
Ellen C. Tran	2134	

SEARCHED			
Class	Subclass	Date	Examiner
713	165	3/30/2007	ECT
380	200	3/30/2007	ECT
380	217	3/30/2007	ECT
380	239	3/30/2007	ECT
380	241	3/30/2007	ECT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	3/30/2007	ECT
INVENTOR	3/30/2007	ECT
NPL - IEEE XPLORE	3/30/2007	ECT
All claims were reviewed for possible 101 rejections	3/30/2007	ECT